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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	858
Number of Logic Elements/Cells	6864
Total RAM Bits	245760
Number of I/O	206
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-LFBGA
Supplier Device Package	256-CABGA (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo3lf-6900c-6bg256i

Features

- **Solutions**
  - Smallest footprint, lowest power, high data throughput bridging solutions for mobile applications
  - Optimized footprint, logic density, IO count, IO performance devices for IO management and logic applications
  - High IO/logic, lowest cost/IO, high IO devices for IO expansion applications

- **Flexible Architecture**
  - Logic Density ranging from 640 to 9.4K LUT4
  - High IO to LUT ratio with up to 384 IO pins

- **Advanced Packaging**
  - 0.4 mm pitch: 1K to 4K densities in very small footprint WLCSP (2.5 mm x 2.5 mm to 3.8 mm x 3.8 mm) with 28 to 63 IOs
  - 0.5 mm pitch: 640 to 6.9K LUT densities in 6 mm x 6 mm to 10 mm x 10 mm BGA packages with up to 281 IOs
  - 0.8 mm pitch: 1K to 9.4K densities with up to 384 IOs in BGA packages

- **Pre-Engineered Source Synchronous I/O**
  - DDR registers in I/O cells
  - Dedicated gearing logic
  - 7:1 Gearing for Display I/Os
  - Generic DDR, DDRx2, DDRx4

- **High Performance, Flexible I/O Buffer**
  - Programmable sysIO™ buffer supports wide range of interfaces:
    - LVCMOS 3.3/2.5/1.8/1.5/1.2
    - LVTTL
    - LVDS, Bus-LVDS, MLVDS, LVPECL
    - MIPI D-PHY Emulated
    - Schmitt trigger inputs, up to 0.5 V hysteresis
  - Ideal for IO bridging applications
  - I/Os support hot socketing
  - On-chip differential termination
  - Programmable pull-up or pull-down mode

- **Flexible On-Chip Clocking**
  - Eight primary clocks
  - Up to two edge clocks for high-speed I/O interfaces (top and bottom sides only)
  - Up to two analog PLLs per device with fractional-n frequency synthesis
    - Wide input frequency range (7 MHz to 400 MHz)

- **Non-volatile, Multi-time Programmable**
  - Instant-on
    - Powers up in microseconds
  - Optional dual boot with external SPI memory
  - Single-chip, secure solution
  - Programmable through JTAG, SPI or I²C
  - MachXO3L includes multi-time programmable NVCM
  - MachXO3LF infinitely reconfigurable Flash
    - Supports background programming of non-volatile memory

- **TransFR Reconfiguration**
  - In-field logic update while IO holds the system state

- **Enhanced System Level Support**
  - On-chip hardened functions: SPI, I²C, timer/counter
  - On-chip oscillator with 5.5% accuracy
  - Unique TraceID for system tracking
  - Single power supply with extended operating range
  - IEEE Standard 1149.1 boundary scan
  - IEEE 1532 compliant in-system programming

- **Applications**
  - Consumer Electronics
  - Compute and Storage
  - Wireless Communications
  - Industrial Control Systems
  - Automotive System

- **Low Cost Migration Path**
  - Migration from the Flash based MachXO3LF to the NVCM based MachXO3L
  - Pin compatible and equivalent timing

Table 1-1. MachXO3L/LF Family Selection Guide

Features		MachXO3L-640/ MachXO3LF-640	MachXO3L-1300/ MachXO3LF-1300	MachXO3L-2100/ MachXO3LF-2100	MachXO3L-4300/ MachXO3LF-4300	MachXO3L-6900/ MachXO3LF-6900	MachXO3L-9400/ MachXO3LF-9400
LUTs		640	1300	2100	4300	6900	9400
Distributed RAM (kbits)		5	10	16	34	54	73
EBR SRAM (kbits)		64	64	74	92	240	432
Number of PLLs		1	1	1	2	2	2
Hardened Functions:	I^2C	2	2	2	2	2	2
	SPI	1	1	1	1	1	1
	Timer/Counter	1	1	1	1	1	1
	Oscillator	1	1	1	1	1	1
MIPI D-PHY Support		Yes	Yes	Yes	Yes	Yes	Yes
Multi Time Programmable NVCM		MachXO3L-640	MachXO3L-1300	MachXO3L-2100	MachXO3L-4300	MachXO3L-6900	MachXO3L-9400
Programmable Flash		MachXO3LF-640	MachXO3LF-1300	MachXO3LF-2100	MachXO3LF-4300	MachXO3LF-6900	MachXO3LF-9400
Packages				**IO**			
36-ball WLCSP[1] (2.5 mm x 2.5 mm, 0.4 mm)			28				
49-ball WLCSP[1] (3.2 mm x 3.2 mm, 0.4 mm)				38			
81-ball WLCSP[1] (3.8 mm x 3.8 mm, 0.4 mm)					63		
121-ball csfBGA[1] (6 mm x 6 mm, 0.5 mm)		100	100	100	100		
256-ball csfBGA[1] (9 mm x 9 mm, 0.5 mm)			206	206	206	206	206
324-ball csfBGA[1] (10 mm x 10 mm, 0.5 mm)				268	268	281	
256-ball caBGA[2] (14 mm x 14 mm, 0.8 mm)			206	206	206	206	206
324-ball caBGA[2] (15 mm x 15 mm, 0.8 mm)				279	279	279	
400-ball caBGA[2] (17 mm x 17 mm, 0.8 mm)					335	335	335
484-ball caBGA[2] (19 mm x 19 mm, 0.8 mm)							384

1. Package is only available for E=1.2 V devices.
2. Package is only available for C=2.5 V/3.3 V devices.

Introduction

MachXO3™ device family is an Ultra-Low Density family that supports the most advanced programmable bridging and IO expansion. It has the breakthrough IO density and the lowest cost per IO. The device IO features have the integrated support for latest industry standard IO.

The MachXO3L/LF family of low power, instant-on, non-volatile PLDs has five devices with densities ranging from 640 to 9400 Look-Up Tables (LUTs). In addition to LUT-based, low-cost programmable logic these devices feature Embedded Block RAM (EBR), Distributed RAM, Phase Locked Loops (PLLs), pre-engineered source synchronous I/O support, advanced configuration support including dual-boot capability and hardened versions of commonly used functions such as SPI controller, I^2C controller and timer/counter. MachXO3LF devices also support User Flash Memory (UFM). These features allow these devices to be used in low cost, high volume consumer and system applications.

The MachXO3L/LF devices are designed on a 65nm non-volatile low power process. The device architecture has several features such as programmable low swing differential I/Os and the ability to turn off I/O banks, on-chip PLLs

Figure 2-5. Primary Clocks for MachXO3L/LF Devices
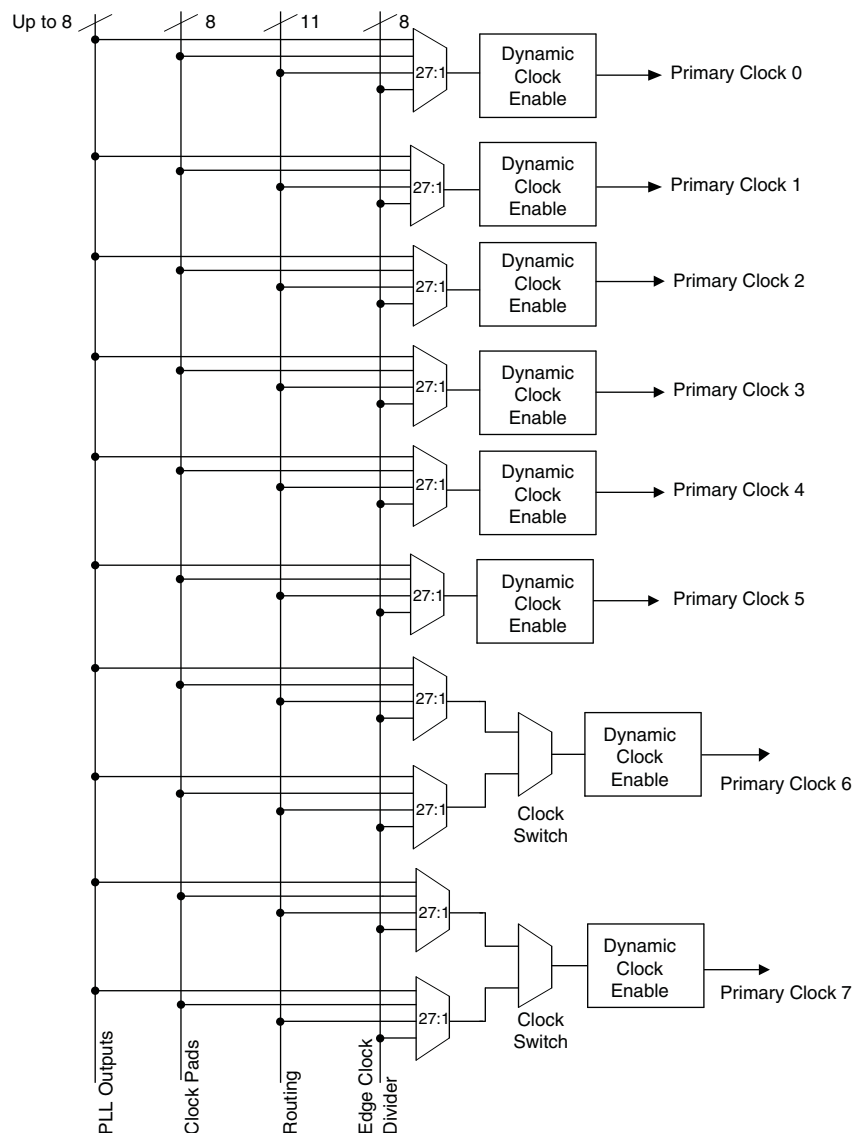
Eight secondary high fanout nets are generated from eight 8:1 muxes as shown in Figure 2-6. One of the eight inputs to the secondary high fanout net input mux comes from dual function clock pins and the remaining seven come from internal routing. The maximum frequency for the secondary clock network is shown in MachXO3L/LF External Switching Characteristics table.

Figure 2-6. Secondary High Fanout Nets for MachXO3L/LF Devices
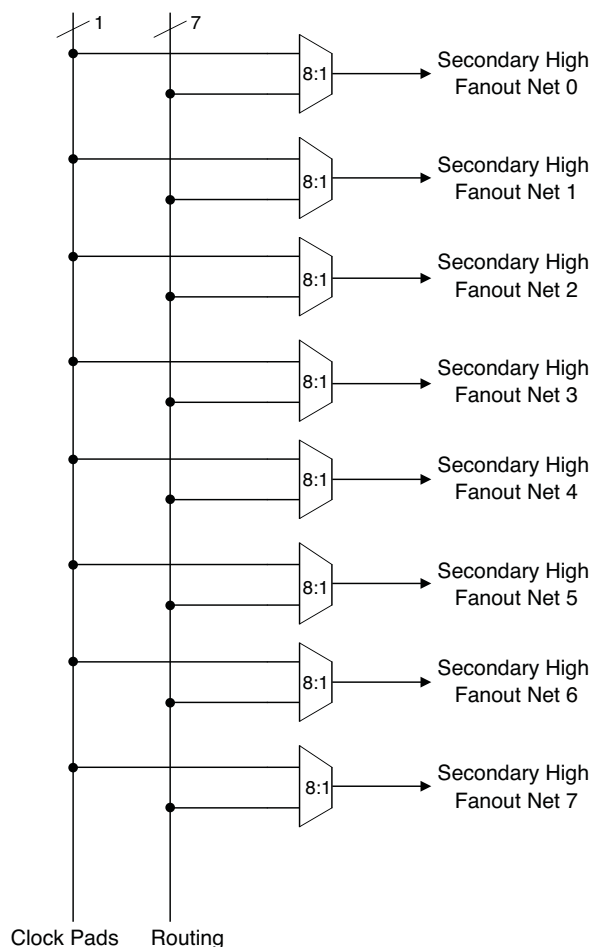
sysCLOCK Phase Locked Loops (PLLs)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. All MachXO3L/LF devices have one or more sysCLOCK PLL. CLKI is the reference frequency input to the PLL and its source can come from an external I/O pin or from internal routing. CLKFB is the feedback signal to the PLL which can come from internal routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The MachXO3L/LF sysCLOCK PLLs support high resolution (16-bit) fractional-N synthesis. Fractional-N frequency synthesis allows the user to generate an output clock which is a non-integer multiple of the input frequency. For more information about using the PLL with Fractional-N synthesis, please see TN1282, MachXO3 sysCLOCK PLL Design and Usage Guide.

Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The output dividers may also be cascaded together to generate low frequency clocks. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the MachXO3L/LF clock distribution network directly or general purpose routing resources can be used.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected. A block diagram of the PLL is shown in Figure 2-7.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock.

This phase shift can be either programmed during configuration or can be adjusted dynamically. In dynamic mode, the PLL may lose lock after a phase adjustment on the output used as the feedback source and not relock until the t_{LOCK} parameter has been satisfied.

The MachXO3L/LF also has a feature that allows the user to select between two different reference clock sources dynamically. This feature is implemented using the PLLREFCS primitive. The timing parameters for the PLL are shown in the sysCLOCK PLL Timing table.

The MachXO3L/LF PLL contains a WISHBONE port feature that allows the PLL settings, including divider values, to be dynamically changed from the user logic. When using this feature the EFB block must also be instantiated in the design to allow access to the WISHBONE ports. Similar to the dynamic phase adjustment, when PLL settings are updated through the WISHBONE port the PLL may lose lock and not relock until the t_{LOCK} parameter has been satisfied. The timing parameters for the PLL are shown in the sysCLOCK PLL Timing table.

For more details on the PLL and the WISHBONE interface, see TN1282, MachXO3 sysCLOCK PLL Design and Usage Guide.
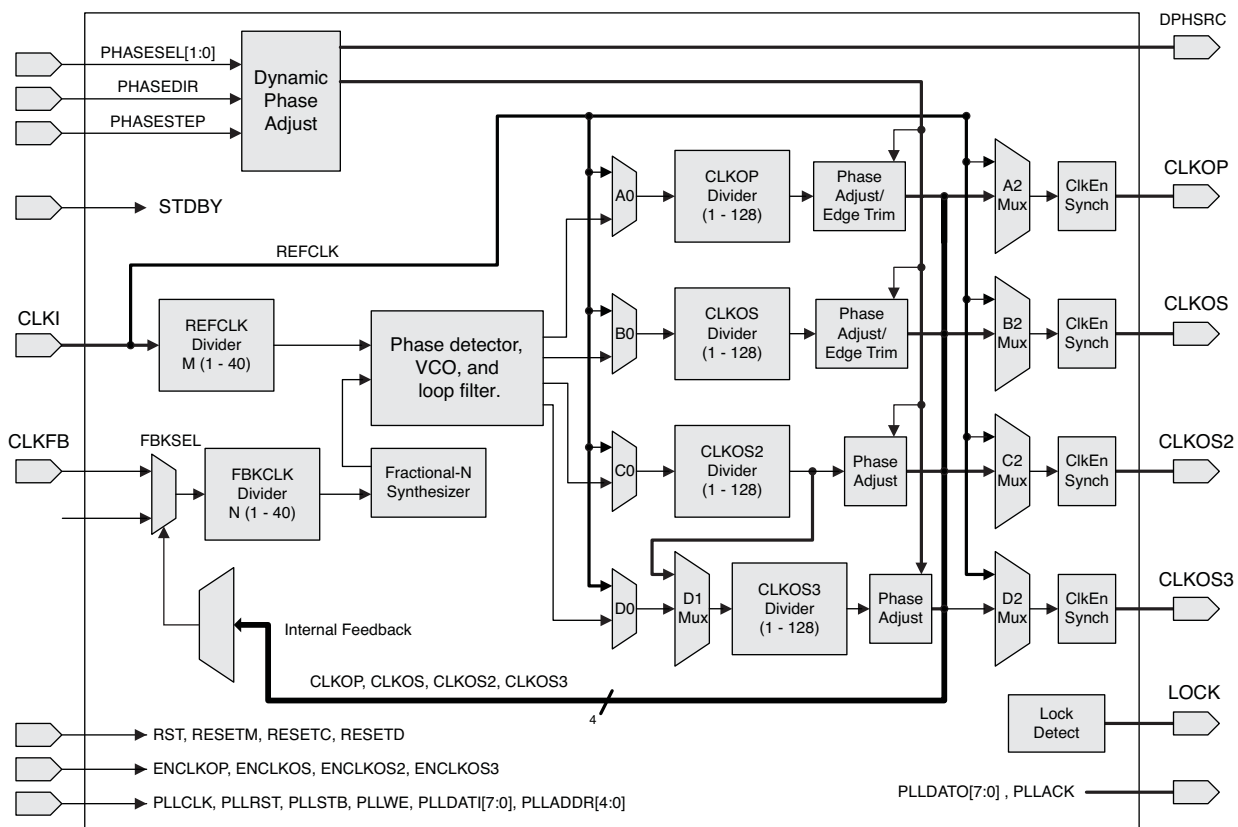
Figure 2-7. PLL Diagram

Table 2-4 provides signal descriptions of the PLL block.

Table 2-4. PLL Signal Descriptions

Port Name	I/O	Description
CLKI	I	Input clock to PLL
CLKFB	I	Feedback clock
PHASESEL[1:0]	I	Select which output is affected by Dynamic Phase adjustment ports
PHASEDIR	I	Dynamic Phase adjustment direction
PHASESTEP	I	Dynamic Phase step – toggle shifts VCO phase adjust by one step.

Table 2-5. sysMEM Block Configurations

Memory Mode	Configurations
Single Port	8,192 x 1 4,096 x 2 2,048 x 4 1,024 x 9
True Dual Port	8,192 x 1 4,096 x 2 2,048 x 4 1,024 x 9
Pseudo Dual Port	8,192 x 1 4,096 x 2 2,048 x 4 1,024 x 9 512 x 18
FIFO	8,192 x 1 4,096 x 2 2,048 x 4 1,024 x 9 512 x 18

Bus Size Matching
All of the multi-port memory modes support different widths on each of the ports. The RAM bits are mapped LSB word 0 to MSB word 0, LSB word 1 to MSB word 1, and so on. Although the word size and number of words for each port varies, this mapping scheme applies to each port.

RAM Initialization and ROM Operation
If desired, the contents of the RAM can be pre-loaded during device configuration. EBR initialization data can be loaded from the NVCM or Configuration Flash.

MachXO3LF EBR initialization data can also be loaded from the UFM. To maximize the number of UFM bits, initialize the EBRs used in your design to an all-zero pattern. Initializing to an all-zero pattern does not use up UFM bits. MachXO3LF devices have been designed such that multiple EBRs share the same initialization memory space if they are initialized to the same pattern.

By preloading the RAM block during the chip configuration cycle and disabling the write controls, the sysMEM block can also be utilized as a ROM.

Memory Cascading
Larger and deeper blocks of RAM can be created using EBR sysMEM Blocks. Typically, the Lattice design tools cascade memory transparently, based on specific design inputs.

**Single, Dual, Pseudo-Dual Port and FIFO Modes**
Figure 2-8 shows the five basic memory configurations and their input/output names. In all the sysMEM RAM modes, the input data and addresses for the ports are registered at the input of the memory array. The output data of the memory is optionally registered at the memory array output.

state. The RPRST signal is used to reset the read pointer. The purpose of this reset is to retransmit the data that is in the FIFO. In these applications it is important to keep careful track of when a packet is written into or read from the FIFO.

Memory Core Reset

The memory core contains data output latches for ports A and B. These are simple latches that can be reset synchronously or asynchronously. RSTA and RSTB are local signals, which reset the output latches associated with port A and port B respectively. The Global Reset (GSRN) signal resets both ports. The output data latches and associated resets for both ports are as shown in Figure 2-9.

Figure 2-9. Memory Core Reset
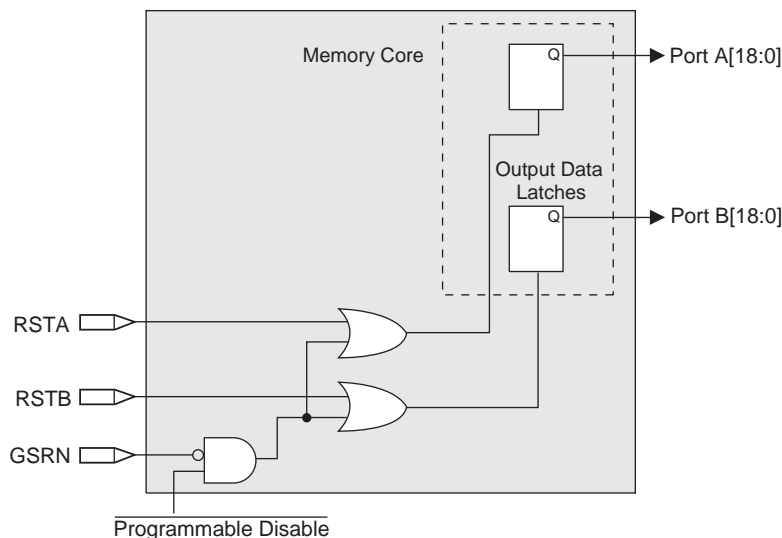
For further information on the sysMEM EBR block, please refer to TN1290, Memory Usage Guide for MachXO3 Devices.

EBR Asynchronous Reset

EBR asynchronous reset or GSR (if used) can only be applied if all clock enables are low for a clock cycle before the reset is applied and released a clock cycle after the reset is released, as shown in Figure 2-10. The GSR input to the EBR is always asynchronous.

Figure 2-10. EBR Asynchronous Reset (Including GSR) Timing Diagram
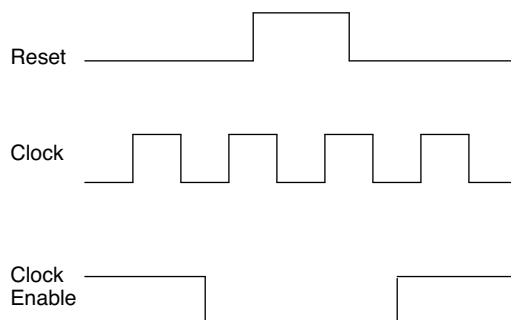
If all clock enables remain enabled, the EBR asynchronous reset or GSR may only be applied and released after the EBR read and write clock inputs are in a steady state condition for a minimum of $1/f_{MAX}$ (EBR clock). The reset release must adhere to the EBR synchronous reset setup time before the next active read or write clock edge.

Figure 2-11. Group of Four Programmable I/O Cells
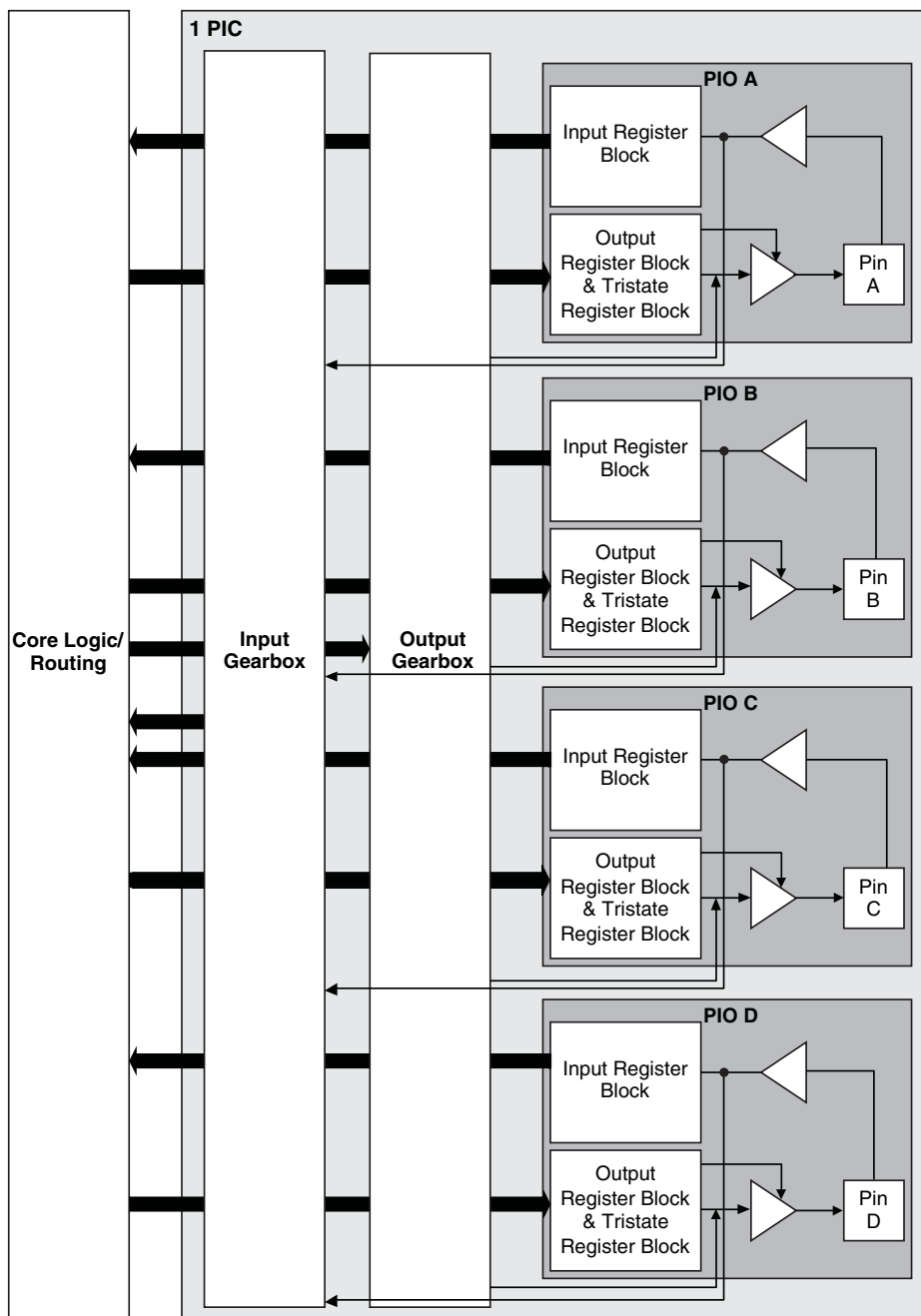
Hardened Timer/Counter

MachXO3L/LF devices provide a hard Timer/Counter IP core. This Timer/Counter is a general purpose, bi-directional, 16-bit timer/counter module with independent output compare units and PWM support. The Timer/Counter supports the following functions:

- Supports the following modes of operation:
  — Watchdog timer
  — Clear timer on compare match
  — Fast PWM
  — Phase and Frequency Correct PWM

- Programmable clock input source

- Programmable input clock prescaler

- One static interrupt output to routing

- One wake-up interrupt to on-chip standby mode controller.

- Three independent interrupt sources: overflow, output compare match, and input capture

- Auto reload

- Time-stamping support on the input capture unit

- Waveform generation on the output

- Glitch-free PWM waveform generation with variable PWM period

- Internal WISHBONE bus access to the control and status registers

- Stand-alone mode with preloaded control registers and direct reset input

Figure 2-20. Timer/Counter Block Diagram
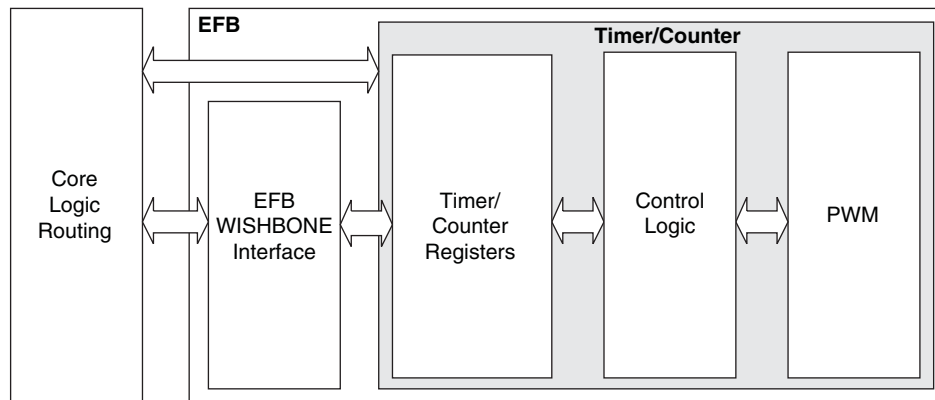
Table 2-16. Timer/Counter Signal Description

Port	I/O	Description
tc_clki	I	Timer/Counter input clock signal
tc_rstn	I	Register tc_rstn_ena is preloaded by configuration to always keep this pin enabled
tc_ic	I	Input capture trigger event, applicable for non-pwm modes with WISHBONE interface. If enabled, a rising edge of this signal will be detected and synchronized to capture tc_cnt value into tc_icr for time-stamping.
tc_int	O	Without WISHBONE – Can be used as overflow flag With WISHBONE – Controlled by three IRQ registers
tc_oc	O	Timer counter output signal

Configuration and Testing

This section describes the configuration and testing features of the MachXO3L/LF family.

IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO3L/LF devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with V_{CCIO} Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, Boundary Scan Testability with Lattice sysIO Capability and TN1087, Minimizing System Interruption During Configuration Using TransFR Technology.

Device Configuration

All MachXO3L/LF devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I²C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO3L/LF device:

1. Internal NVCM/Flash Download

2. JTAG

3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory

4. System microprocessor to drive a serial slave SPI port (SSPI mode)

5. Standard I²C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1279, MachXO3 Programming and Configuration Usage Guide for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO3L/LF devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip NVCM/Flash, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip NVCM/Flash. For more details, refer to TN1279, MachXO3 Programming and Configuration Usage Guide.

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1279, MachXO3 Programming and Configuration Usage Guide.

TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, Minimizing System Interruption During Configuration Using TransFR Technology for details.

DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
I_{IL}, I_{IH}[1, 4]	Input or I/O Leakage	Clamp OFF and $V_{CCIO} < V_{IN} < V_{IH}$ (MAX)	—	—	+175	µA
		Clamp OFF and $V_{IN} = V_{CCIO}$	−10	—	10	µA
		Clamp OFF and V_{CCIO} - 0.97 V < V_{IN} < V_{CCIO}	−175	—	—	µA
		Clamp OFF and 0 V < V_{IN} < V_{CCIO} - 0.97 V	—	—	10	µA
		Clamp OFF and V_{IN} = GND	—	—	10	µA
		Clamp ON and 0 V < V_{IN} < V_{CCIO}	—	—	10	µA
I_{PU}	I/O Active Pull-up Current	$0 < V_{IN} < 0.7\ V_{CCIO}$	−30	—	−309	µA
I_{PD}	I/O Active Pull-down Current	V_{IL} (MAX) < V_{IN} < V_{CCIO}	30	—	305	µA
I_{BHLS}	Bus Hold Low sustaining current	$V_{IN} = V_{IL}$ (MAX)	30	—	—	µA
I_{BHHS}	Bus Hold High sustaining current	$V_{IN} = 0.7 V_{CCIO}$	−30	—	—	µA
I_{BHLO}	Bus Hold Low Overdrive current	$0 \le V_{IN} \le V_{CCIO}$	—	—	305	µA
I_{BHHO}	Bus Hold High Overdrive current	$0 \le V_{IN} \le V_{CCIO}$	—	—	−309	µA
V_{BHT}[3]	Bus Hold Trip Points		V_{IL} (MAX)	—	V_{IH} (MIN)	V
C1	I/O Capacitance[2]	V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = Typ., V_{IO} = 0 to V_{IH} (MAX)	3	5	9	pf
C2	Dedicated Input Capacitance[2]	V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = Typ., V_{IO} = 0 to V_{IH} (MAX)	3	5.5	7	pf
V_{HYST}	Hysteresis for Schmitt Trigger Inputs[5]	V_{CCIO} = 3.3 V, Hysteresis = Large	—	450	—	mV
		V_{CCIO} = 2.5 V, Hysteresis = Large	—	250	—	mV
		V_{CCIO} = 1.8 V, Hysteresis = Large	—	125	—	mV
		V_{CCIO} = 1.5 V, Hysteresis = Large	—	100	—	mV
		V_{CCIO} = 3.3 V, Hysteresis = Small	—	250	—	mV
		V_{CCIO} = 2.5 V, Hysteresis = Small	—	150	—	mV
		V_{CCIO} = 1.8 V, Hysteresis = Small	—	60	—	mV
		V_{CCIO} = 1.5 V, Hysteresis = Small	—	40	—	mV

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2. T_A 25 °C, f = 1.0 MHz.
3. Please refer to V_{IL} and V_{IH} in the sysIO Single-Ended DC Electrical Characteristics table of this document.
4. When V_{IH} is higher than V_{CCIO}, a transient current typically of 30 ns in duration or less with a peak current of 6mA can occur on the high-to-low transition. For true LVDS output pins in MachXO3L/LF devices, V_{IH} must be less than or equal to V_{CCIO}.
5. With bus keeper circuit turned on. For more details, refer to TN1280, MachXO3 sysIO Usage Guide.

sysIO Differential Electrical Characteristics

The LVDS differential output buffers are available on the top side of the MachXO3L/LF PLD family.

LVDS

Over Recommended Operating Conditions

Parameter Symbol	Parameter Description	Test Conditions	Min.	Typ.	Max.	Units
V_{INP}, V_{INM}	Input Voltage	V_{CCIO} = 3.3 V	0	—	2.605	V
		V_{CCIO} = 2.5 V	0	—	2.05	V
V_{THD}	Differential Input Threshold		±100	—		mV
V_{CM}	Input Common Mode Voltage	V_{CCIO} = 3.3 V	0.05	—	2.6	V
		V_{CCIO} = 2.5 V	0.05	—	2.0	V
I_{IN}	Input current	Power on	—	—	±10	μA
V_{OH}	Output high voltage for V_{OP} or V_{OM}	R_T = 100 Ohm	—	1.375	—	V
V_{OL}	Output low voltage for V_{OP} or V_{OM}	R_T = 100 Ohm	0.90	1.025	—	V
V_{OD}	Output voltage differential	(V_{OP} - V_{OM}), R_T = 100 Ohm	250	350	450	mV
ΔV_{OD}	Change in V_{OD} between high and low		—	—	50	mV
V_{OS}	Output voltage offset	(V_{OP} - V_{OM})/2, R_T = 100 Ohm	1.125	1.20	1.395	V
ΔV_{OS}	Change in V_{OS} between H and L		—	—	50	mV
I_{OSD}	Output short circuit current	V_{OD} = 0 V driver outputs shorted	—	—	24	mA

Typical Building Block Function Performance – C/E Devices[1]

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	–6 Timing	Units
Basic Functions		
16-bit decoder	8.9	ns
4:1 MUX	7.5	ns
16:1 MUX	8.3	ns

Register-to-Register Performance

Function	–6 Timing	Units
Basic Functions		
16:1 MUX	412	MHz
16-bit adder	297	MHz
16-bit counter	324	MHz
64-bit counter	161	MHz
Embedded Memory Functions		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	183	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (one PFU)	500	MHz

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.

Derating Logic Timing

Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.

Parameter	Description	Device	\-6 Min.	\-6 Max.	\-5 Min.	\-5 Max.	Units
General I/O Pin Parameters (Using Edge Clock without PLL)							
t_{COE}	Clock to Output - PIO Output Register	MachXO3L/LF-1300	—	7.53	—	7.76	ns
		MachXO3L/LF-2100	—	7.53	—	7.76	ns
		MachXO3L/LF-4300	—	7.45	—	7.68	ns
		MachXO3L/LF-6900	—	7.53	—	7.76	ns
		MachXO3L/LF-9400	—	8.93	—	9.35	ns
t_{SUE}	Clock to Data Setup - PIO Input Register	MachXO3L/LF-1300	−0.19	—	−0.19	—	ns
		MachXO3L/LF-2100	−0.19	—	−0.19	—	ns
		MachXO3L/LF-4300	−0.16	—	−0.16	—	ns
		MachXO3L/LF-6900	−0.19	—	−0.19	—	ns
		MachXO3L/LF-9400	−0.20	—	−0.20	—	ns
t_{HE}	Clock to Data Hold - PIO Input Register	MachXO3L/LF-1300	1.97	—	2.24	—	ns
		MachXO3L/LF-2100	1.97	—	2.24	—	ns
		MachXO3L/LF-4300	1.89	—	2.16	—	ns
		MachXO3L/LF-6900	1.97	—	2.24	—	ns
		MachXO3L/LF-9400	1.98	—	2.25	—	ns
t_{SU_DELE}	Clock to Data Setup - PIO Input Register with Data Input Delay	MachXO3L/LF-1300	1.56	—	1.69	—	ns
		MachXO3L/LF-2100	1.56	—	1.69	—	ns
		MachXO3L/LF-4300	1.74	—	1.88	—	ns
		MachXO3L/LF-6900	1.66	—	1.81	—	ns
		MachXO3L/LF-9400	1.71	—	1.85	—	ns
t_{H_DELE}	Clock to Data Hold - PIO Input Register with Input Data Delay	MachXO3L/LF-1300	−0.23	—	−0.23	—	ns
		MachXO3L/LF-2100	−0.23	—	−0.23	—	ns
		MachXO3L/LF-4300	−0.34	—	−0.34	—	ns
		MachXO3L/LF-6900	−0.29	—	−0.29	—	ns
		MachXO3L/LF-9400	−0.30	—	−0.30	—	ns
General I/O Pin Parameters (Using Primary Clock with PLL)							
t_{COPLL}	Clock to Output - PIO Output Register	MachXO3L/LF-1300	—	5.98	—	6.01	ns
		MachXO3L/LF-2100	—	5.98	—	6.01	ns
		MachXO3L/LF-4300	—	5.99	—	6.02	ns
		MachXO3L/LF-6900	—	6.02	—	6.06	ns
		MachXO3L/LF-9400	—	5.55	—	6.13	ns
t_{SUPLL}	Clock to Data Setup - PIO Input Register	MachXO3L/LF-1300	0.36	—	0.36	—	ns
		MachXO3L/LF-2100	0.36	—	0.36	—	ns
		MachXO3L/LF-4300	0.35	—	0.35	—	ns
		MachXO3L/LF-6900	0.34	—	0.34	—	ns
		MachXO3L/LF-9400	0.33	—	0.33	—	ns
t_{HPLL}	Clock to Data Hold - PIO Input Register	MachXO3L/LF-1300	0.42	—	0.49	—	ns
		MachXO3L/LF-2100	0.42	—	0.49	—	ns
		MachXO3L/LF-4300	0.43	—	0.50	—	ns
		MachXO3L/LF-6900	0.46	—	0.54	—	ns
		MachXO3L/LF-9400	0.47	—	0.55	—	ns

| Parameter	Description	Device	–6 Min.	–6 Max.	–5 Min.	–5 Max.	Units
Generic DDRX1 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX1_RX.SCLK.Aligned[8, 9]							
t_{DVA}	Input Data Valid After CLK	All MachXO3L/LF devices, all sides	—	0.317	—	0.344	UI
t_{DVE}	Input Data Hold After CLK		0.742	—	0.702	—	UI
f_{DATA}	DDRX1 Input Data Speed		—	300	—	250	Mbps
f_{DDRX1}	DDRX1 SCLK Frequency		—	150	—	125	MHz
Generic DDRX1 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX1_RX.SCLK.Centered[8, 9]							
t_{SU}	Input Data Setup Before CLK	All MachXO3L/LF devices, all sides	0.566	—	0.560	—	ns
t_{HO}	Input Data Hold After CLK		0.778	—	0.879	—	ns
f_{DATA}	DDRX1 Input Data Speed		—	300	—		Mbps
f_{DDRX1}	DDRX1 SCLK Frequency		—	150	—	125	MHz
Generic DDRX2 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX2_RX.ECLK.Aligned[8, 9]							
t_{DVA}	Input Data Valid After CLK	MachXO3L/LF devices, bottom side only	—	0.316	—	0.342	UI
t_{DVE}	Input Data Hold After CLK		0.710	—	0.675	—	UI
f_{DATA}	DDRX2 Serial Input Data Speed		—	664	—	554	Mbps
f_{DDRX2}	DDRX2 ECLK Frequency		—	332	—	277	MHz
f_{SCLK}	SCLK Frequency		—	166	—	139	MHz
Generic DDRX2 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX2_RX.ECLK.Centered[8, 9]							
t_{SU}	Input Data Setup Before CLK	MachXO3L/LF devices, bottom side only	0.233	—	0.219	—	ns
t_{HO}	Input Data Hold After CLK		0.287	—	0.287	—	ns
f_{DATA}	DDRX2 Serial Input Data Speed		—	664	—	554	Mbps
f_{DDRX2}	DDRX2 ECLK Frequency		—	332	—	277	MHz
f_{SCLK}	SCLK Frequency		—	166	—	139	MHz
Generic DDR4 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX4_RX.ECLK.Aligned[8]							
t_{DVA}	Input Data Valid After ECLK	MachXO3L/LF devices, bottom side only	—	0.307	—	0.320	UI
t_{DVE}	Input Data Hold After ECLK		0.782	—	0.699	—	UI
f_{DATA}	DDRX4 Serial Input Data Speed		—	800	—	630	Mbps
f_{DDRX4}	DDRX4 ECLK Frequency		—	400	—	315	MHz
f_{SCLK}	SCLK Frequency		—	100	—	79	MHz
Generic DDR4 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX4_RX.ECLK.Centered[8]							
t_{SU}	Input Data Setup Before ECLK	MachXO3L/LF devices, bottom side only	0.233	—	0.219	—	ns
t_{HO}	Input Data Hold After ECLK		0.287	—	0.287	—	ns
f_{DATA}	DDRX4 Serial Input Data Speed		—	800	—	630	Mbps
f_{DDRX4}	DDRX4 ECLK Frequency		—	400	—	315	MHz
f_{SCLK}	SCLK Frequency		—	100	—	79	MHz
7:1 LVDS Inputs (GDDR71_RX.ECLK.7:1)[9]							
t_{DVA}	Input Data Valid After ECLK	MachXO3L/LF devices, bottom side only	—	0.290	—	0.320	UI
t_{DVE}	Input Data Hold After ECLK		0.739	—	0.699	—	UI
f_{DATA}	DDR71 Serial Input Data Speed		—	756	—	630	Mbps
f_{DDR71}	DDR71 ECLK Frequency		—	378	—	315	MHz
f_{CLKIN}	7:1 Input Clock Frequency (SCLK) (minimum limited by PLL)		—	108	—	90	MHz

Figure 3-6. Receiver GDDR71_RX. Waveforms
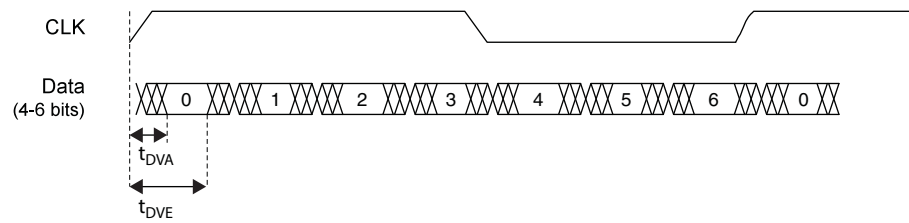
Figure 3-7. Transmitter GDDR71_TX. Waveforms
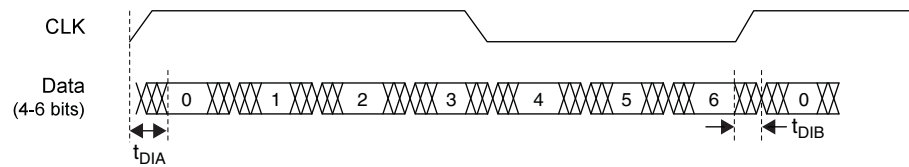
sysCONFIG Port Timing Specifications

Symbol	Parameter		Min.	Max.	Units
All Configuration Modes					
t_{PRGM}	PROGRAMN low pulse accept		55	—	ns
t_{PRGMJ}	PROGRAMN low pulse rejection		—	25	ns
t_{INITL}	INITN low time	LCMXO3L/LF-640/ LCMXO3L/LF-1300	—	55	us
		LCMXO3L/LF-1300 256-Ball Package/ LCMXO3L/LF-2100	—	70	us
		LCMXO3L/LF-2100 324-Ball Package/ LCMXO3-4300	—	105	us
		LCMXO3L/LF-4300 400-Ball Package/ LCMXO3-6900	—	130	us
		LCMXO3L/LF-9400C	—	175	us
$t_{DPPINIT}$	PROGRAMN low to INITN low		—	150	ns
$t_{DPPDONE}$	PROGRAMN low to DONE low		—	150	ns
t_{IODISS}	PROGRAMN low to I/O disable		—	120	ns
Slave SPI					
f_{MAX}	CCLK clock frequency		—	66	MHz
t_{CCLKH}	CCLK clock pulse width high		7.5	—	ns
t_{CCLKL}	CCLK clock pulse width low		7.5	—	ns
t_{STSU}	CCLK setup time		2	—	ns
t_{STH}	CCLK hold time		0	—	ns
t_{STCO}	CCLK falling edge to valid output		—	10	ns
t_{STOZ}	CCLK falling edge to valid disable		—	10	ns
t_{STOV}	CCLK falling edge to valid enable		—	10	ns
t_{SCS}	Chip select high time		25	—	ns
t_{SCSS}	Chip select setup time		3	—	ns
t_{SCSH}	Chip select hold time		3	—	ns
Master SPI					
f_{MAX}	MCLK clock frequency		—	133	MHz
t_{MCLKH}	MCLK clock pulse width high		3.75	—	ns
t_{MCLKL}	MCLK clock pulse width low		3.75	—	ns
t_{STSU}	MCLK setup time		5	—	ns
t_{STH}	MCLK hold time		1	—	ns
t_{CSSPI}	INITN high to chip select low		100	200	ns
t_{MCLK}	INITN high to first MCLK edge		0.75	1	us

Signal Descriptions

Signal Name	I/O	Descriptions
General Purpose		
P[Edge] [Row/Column Number]_[A/B/C/D]	I/O	[Edge] indicates the edge of the device on which the pad is located. Valid edge designations are L (Left), B (Bottom), R (Right), T (Top).
		[Row/Column Number] indicates the PFU row or the column of the device on which the PIO Group exists. When Edge is T (Top) or (Bottom), only need to specify Row Number. When Edge is L (Left) or R (Right), only need to specify Column Number.
		[A/B/C/D] indicates the PIO within the group to which the pad is connected.
		Some of these user-programmable pins are shared with special function pins. When not used as special function pins, these pins can be programmed as I/Os for user logic.
		During configuration of the user-programmable I/Os, the user has an option to tri-state the I/Os and enable an internal pull-up, pull-down or buskeeper resistor. This option also applies to unused pins (or those not bonded to a package pin). The default during configuration is for user-programmable I/Os to be tri-stated with an internal pull-down resistor enabled. When the device is erased, I/Os will be tri-stated with an internal pull-down resistor enabled. Some pins, such as PROGRAMN and JTAG pins, default to tri-stated I/Os with pull-up resistors enabled when the device is erased.
NC	—	No connect.
GND	—	GND – Ground. Dedicated pins. It is recommended that all GNDs are tied together.
VCC	—	V_{CC} – The power supply pins for core logic. Dedicated pins. It is recommended that all VCCs are tied to the same supply.
VCCIOx	—	VCCIO – The power supply pins for I/O Bank x. Dedicated pins. It is recommended that all VCCIOs located in the same bank are tied to the same supply.
PLL and Clock Functions (Used as user-programmable I/O pins when not used for PLL or clock pins)		
[LOC]_GPLL[T, C]_IN	—	Reference Clock (PLL) input pads: [LOC] indicates location. Valid designations are L (Left PLL) and R (Right PLL). T = true and C = complement.
[LOC]_GPLL[T, C]_FB	—	Optional Feedback (PLL) input pads: [LOC] indicates location. Valid designations are L (Left PLL) and R (Right PLL). T = true and C = complement.
PCLK [n]_[2:0]	—	Primary Clock pads. One to three clock pads per side.
Test and Programming (Dual function pins used for test access port and during sysCONFIG™)		
TMS	I	Test Mode Select input pin, used to control the 1149.1 state machine.
TCK	I	Test Clock input pin, used to clock the 1149.1 state machine.
TDI	I	Test Data input pin, used to load data into the device using an 1149.1 state machine.
TDO	O	Output pin – Test Data output pin used to shift data out of the device using 1149.1.
JTAGENB	I	Optionally controls behavior of TDI, TDO, TMS, TCK. If the device is configured to use the JTAG pins (TDI, TDO, TMS, TCK) as general purpose I/O, then:
		If JTAGENB is low: TDI, TDO, TMS and TCK can function a general purpose I/O.
		If JTAGENB is high: TDI, TDO, TMS and TCK function as JTAG pins.
		For more details, refer to TN1279, MachXO3 Programming and Configuration Usage Guide.

Date	Version	Section	Change Summary
September 2015	1.5	DC and Switching Characteristics	Updated the MIPI D-PHY Emulation section. Revised Table 3-5, MIPI D-PHY Output DC Conditions. — Revised RL Typ. value. — Revised RH description and values.
			Updated the Maximum sysIO Buffer Performance section. Revised MIPI Max. Speed value.
			Updated the MachXO3L/LF External Switching Characteristics – C/E Devices section. Added footnotes 14 and 15.
August 2015	1.4	Architecture	Updated the Device Configuration section. Added JTAGENB to TAP dual purpose pins.
		Ordering Information	Updated the top side markings section to indicate the use of LMXO3LF for the LCMXO3LF device.
March 2015	1.3	All	General update. Added MachXO3LF devices.
October 2014	1.2	Introduction	Updated Table 1-1, MachXO3L Family Selection Guide. Revised XO3L-2100 and XO3L-4300 IO for 324-ball csfBGA package.
		Architecture	Updated the Dual Boot section. Corrected information on where the primary bitstream and the golden image must reside.
		Pinout Information	Updated the Pin Information Summary section.
			Changed General Purpose IO Bank 5 values for MachXO3L-2100 and MachXO3L-4300 CSFBGA 324 package.
			Changed Number 7:1 or 8:1 Gearboxes for MachXO3L-640 and MachXO3L-1300.
			Removed DQS Groups (Bank 1) section.
			Changed VCCIO Pins Bank 1 values for MachXO3L-1300, MachXO3L-2100, MachXO3L-4300 and MachXO3L-6900 CSFBGA 256 package.
			Changed GND values for MachXO3L-1300, MachXO3L-2100, MachXO3L-4300 and MachXO3L-6900 CSFBGA 256 package.
			Changed NC values for MachXO3L-2100 and MachXO3L-4300 CSFBGA 324 package.
		DC and Switching Characteristics	Updated the BLVDS section. Changed output impedance nominal values in Table 3-2, BLVDS DC Condition.
			Updated the LVPECL section. Changed output impedance nominal value in Table 3-3, LVPECL DC Condition.
			Updated the sysCONFIG Port Timing Specifications section. Updated INITN low time values.
July 2014	1.1	DC and Switching Characteristics	Updated the Static Supply Current – C/E Devices section. Added devices.
			Updated the Programming and Erase Supply Current – C/E Device section. Added devices.
			Updated the sysIO Single-Ended DC Electrical Characteristics section. Revised footnote 4.
			Added the NVCM Download Time section.
			Updated the Typical Building Block Function Performance – C/E Devices section. Added information to footnote.
		Pinout Information	Updated the Pin Information Summary section.
		Ordering Information	Updated the MachXO3L Part Number Description section. Added packages.
			Updated the Ordering Information section. General update.

Date	Version	Section	Change Summary
June 2014	1.0	—	Product name/trademark adjustment.
		Introduction	Updated Features section.
			Updated Table 1-1, MachXO3L Family Selection Guide. Changed fcCSP packages to csfBGA. Adjusted 121-ball csfBGA arrow.
			Introduction section general update.
		Architecture	General update.
		DC and Switching Characteristics	Updated sysIO Recommended Operating Conditions section. Removed V_{REF} (V) column. Added standards.
			Updated Maximum sysIO Buffer Performance section. Added MIPI I/O standard.
			Updated MIPI D-PHY Emulation section. Changed Low Speed to Low Power. Updated Table 3-4, MIPI DC Conditions.
			Updated Table 3-5, MIPI D-PHY Output DC Conditions.
			Updated Maximum sysIO Buffer Performance section.
			Updated MachXO3L External Switching Characteristics – C/E Device section.
May 2014	00.3	Introduction	Updated Features section.
			Updated Table 1-1, MachXO3L Family Selection Guide. Moved 121-ball fcCSP arrow.
			General update of Introduction section.
		Architecture	General update.
		Pinout Information	Updated Pin Information Summary section. Updated or added data on WLCSP49, WLCSP81, CABGA324, and CABGA400 for specific devices.
		Ordering Information	Updated MachXO3L Part Number Description section. Updated or added data on WLCSP49, WLCSP81, CABGA324, and CABGA400 for specific devices.
			Updated Ultra Low Power Commercial and Industrial Grade Devices, Halogen Free (RoHS) Packaging section. Added part numbers.
February 2014	00.2	DC and Switching Characteristics	Updated MachXO3L External Switching Characteristics – C/E Devices table. Removed LPDDR and DDR2 parameters.
	00.1	—	Initial release.